East Sauch History (Gpp) (5/30/04) Je.

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	L-Number			DB	Time stamp
٨.	_	5	039404.ap.	USPAT;	2004/05/29 15:01
,	क्रिका का			US-PGPUB;	
				EPO; JPO;	
	120		3	DERWENT;	*
1	- ·	4	039484.ap.	USPAT:	2003/09/07 12:04
3.	8			US-PGPUB;	2003/03/07 12:04
				EPO; JPO;	
				DERWENT;	
	_	28	method near4 circuit adj simulation.clm.	IBM_TDB	
	120		method hear4 circuit adj simulation.cim.	USPAT;	2003/09/07 12:08
	de_		d .	US-PGPUB; EPO; JPO;	
				DERWENT;	
	5 45			IBM TDB	
	· <del>-</del> ` *	0	apparatus near6 computer adj simulation	USPĀT;	2003/09/07 12:09
	博		near6 circuit.clm.	US-PGPUB;	
	No and the			EPO; JPO;	
	G		,	DERWENT; IBM TDB	
	- ,	162	computer adj system near6 simulation.clm.	USPAT;	2003/09/07 12:10
.		11.		US-PGPUB;	2,003,03,01 12:10
		1 1		EPO; JPO;	
	•	P 2		DERWENT;	
Í	<u>_</u> -	8	/US-200301E40C4 C UG 000001E4066 A	IBM_TDB	
1	4		(US-20030154064-\$ or US-20030154065-\$ or US-20030154453-\$ or	US-PGPUB	2003/09/07 12:42
	2.1		US-20030154454-\$ or US-20030163277-\$ or		1
			US-20030163510-\$ or US-20030164239-\$).did.		·
-	<b>- ***</b>	0	simulating.clm and apparatus.clm. and	USPAT;	2003/09/07 12:43
			design.clm.	US-PGPUB	
nr., e	基	840	simulating near6 circuit.clm.	USPAT;	2003/09/07 12:44
ŀ	<u>-</u> , .	7	(US-20030154453-\$ or US-20030154454-\$ or	US-PGPUB	
			US-20030163277-\$ or US-20030163510-\$ or	US-PGPUB	2004/05/19 11:21
	1		US-20030154447-\$ or US-20030154065-\$ or		
			US-20030154064-\$).did.		
- [	<del>=</del> 4 - 47 - 1	. 1136	((703/13) or (703/14)).CCLs.	USPAT;	2004/05/19 13:54
		42	1117021121	US-PGPUB	
		42	(((703/13) or (703/14)).CCLS.) and method near6 capacitance	USPAT;	2004/05/19 14:16
			nearo capacitance	US-PGPUB; EPO; JPO;	
	<b>4</b>			DERWENT;	
				IBM TDB	
	-	0	(((703/13) or (703/14)).CCLS.) and method	USPAT;	2004/05/19 14:21
	1		near6 capacitance and simulat\$3 near6	US-PGPUB;	
٠ [ .			design adj structure	EPO; JPO;	
1				DERWENT; IBM TDB	
1.	- '	· o	method near6 capacitance near6 simulat\$3	USPAT;	2004/05/19 15:16
	23		and simul\$3 near6 design adj structure and	US-PGPUB;	2004/03/13 13:10
			parasitic adj capacitance	EPO; JPO;	
	: - 4			DERWENT;	
		0	method nears connectors	IBM_TDB	
		,	method near6 capacitance near6 simulat\$3 and simul\$3 near6 design adj structure.	USPAT;	2004/05/19 15:16
			dimuryo medio design adj structure	US-PGPUB; EPO; JPO;	
1	•	·		DERWENT;	
		1		IBM TDB	
.	- :	1814	circuit near3 simulat\$3.clm.	USPĀT;	2004/05/19 15:16
				US-PGPUB;	
				EPO; JPO;	•
				DERWENT; IBM TDB	•
-	-	95	circuit near3 simulat\$3.clm. and method	USPAT;	2004/05/19 15:35
	. [		near6 (capacitance capacitor)	US-PGPUB;	-501/05/19 13:33
1.		ļ		EPO; JPO;	
	- 44	İ		DERWENT;	1
	· · · · · · · · · · · · · · · · · · ·	- <u> </u>		IBM TDB	

			the contract of the contract o	t .		
	- 'AB'	34	Telegraphic mode of the track o	USPAT;	2004/05/19 17:26	<u></u>
	1 .	1	near6 (capacitance capacitor) and design	US-PGPUB;		Ì
a) ;	72 13	.	near6 simulat\$3	EPO; JPO;	•	
			9	DERWENT;		i
		15	المراجعة الم	IBM_TDB		1
		. 13	gallia.in. near6 james.in.	USPAT;	2004/05/19 17:29	.
				US-PGPUB;	3.	
-	-			EPO; JPO;	· 1	1
	*	1		DERWENT;		
	- *	5	gallia.in. near6 james.in. and design\$3	IBM_TDB	000440545	
			and capacitance	USPAT; US-PGPUB;	2004/05/19 17:31	
				EPO; JPO;		
	100			DERWENT;		1
-	•			IBM TDB	1.00	1
	<del>-</del>	19	T THE CADACTERING	USPAT;	2004/05/19 17:33	1
			near20 (circuit near2	US-PGPUB;		1
.			simulat\$3).ti,ab,clm.	EPO; JPO;		
				DERWENT;		ŀ
-	<u></u>	7	/dominance determinance	IBM_TDB		-
	ξ·	1 4 4 7	(design\$3 determin\$3) near3 capacitance near20 (circuit near2	USPAT;	2004/05/20 10:38	1
			simulat\$3).ti,ab,clm. and	US-PGPUB;		
- 1			parasitic.ti,ab,clm.	EPO; JPO; DERWENT;		1
ļ			1	IBM TDB		1
- 1		1137	((703/13) or (703/14)).CCLS.	USPAT;	2004/05/20 10:38	
	€2			US-PGPUB;	2004/05/20 10:38	
		1.		EPO; JPO;		1
-				DERWENT;		
1				IBM TDB		1
	_	58	(((703/13) or (703/14)).CCLS.) and circuit	USPAT;	2004/05/20 10:51	1
			adj simulati\$2 and design and capacitance	US-PGPUB;		ŀ
		· May and	and parasitic	EPO; JPO;		ĺ
-	.5			DERWENT;		1
1	<del>-</del> :		(((703/13)  or  (703/14)).CCLS.) and circuit	IBM TDB	000000000000000000000000000000000000000	ŀ
			adj simulati\$2 and design adj structure	USPAT; US-PGPUB;	2004/05/20 10:52	ĺ
1		1	and test adj structure and capacitance	EPO; JPO;		
	Æ.			DERWENT;		l
-	•			IBM TDB		ļ
1	- '	0	(((703/13) or (703/14)).CCLS.) and circuit	USPAT;	2004/05/20 10:52	ĺ
	٠		adj simulati\$2 and design adj structure	US-PGPUB;		
			and test adj structure	EPO; JPO;		İ
1				DERWENT;	]	1
	<u> </u>	158	((((703/13) or (703/14)).CCLS.) and circuit	IBM TDB		
	- 5 ·		adj simulati\$2 and design and test	USPAT; US-PGPUB;	2004/05/20 10:52	l
			January and Google	EPO; JPO;		ĺ
				DERWENT;		١.
				IBM TDB		
	<del>-</del>	8	(((703/13) or (703/14)).CCLS.) and circuit	USPĀT;	2004/05/20 11:10	
			adj simulati\$2 and design and test and	US-PGPUB;		
1.		1	capacitance and parasitic adj capacitance	EPO; JPO;		
		- 1		DERWENT;		
١.	-	4	(((703/13) or (703/14)).CCLS.) and circuit	IBM_TDB		
			adj simulati\$2 and design and test and	USPAT;	2004/05/20 11:18	
			capacitance and (wire interconnect) adj	US-PGPUB; EPO; JPO;	·	
ĺ			capacitance	DERWENT;	1	
				IBM TDB	•	
-	-	0	estimat\$3 near2 parasitic adj capacitance	USPAT;	2004/05/20 11:19	
ļ			near8 test	US-PGPUB;		
		, , ,		EPO; JPO;		
	***			DERWENT;		
-	_	37	estimat\$3 near2 narroitia add	IBM_TDB		
		3,	estimat\$3 near2 parasitic adj capacitance	USPAT;	2004/05/20 11:19	
		46.		US-PGPUB; EPO; JPO;		
	İ	1		DERWENT;		
		<u> </u>		IBM TDB		٠.

	-		estimat\$3 near2 parasitic adj capacitance	USPAT;	2004/05/20 11:20
			and test adj structure	US-PGPUB;	
				EPO; JPO;	
	E .			DERWENT;	
		1 .	estimat\$3 near2 parasitic adj capacitance	IBM_TDB	
	į		and test adj (device transistor capacitor)	USPAT; US-PGPUB;	2004/05/20 11:22
		·	and odd day (device transfistor capacitor)	EPO; JPO;	
				DERWENT;	
	er.			IBM TDB	
	-	12	estimat\$3 near2 parasitic adj capacitance	USPAT;	2004/05/20 14:10
			and simulation	US-PGPUB;	
				EPO; JPO;	
	ļ			DERWENT;	
	1 _		("6243653").PN.	IBM_TDB	
		4	( 0243033 ) . PN.	USPAT;	2004/05/20 15:35
	at:			US-PGPUB;	
	-			EPO; JPO; DERWENT;	
	ĺ			IBM TOB	
	<del>-</del> ,	6	extraction near4 parasitic adj	USPAT;	2004/05/20 15:36
	· æ	1.	capacitance.ti,ab,clm.	US-PGPUB;	1,2001,00720 13.30
				EPO; JPO;	
		7		DERWENT;	
				IBM_TDB	
. :		4	extraction near4 parasitic adj	USPAT;	2004/05/20 15:36
:			capacitance.ti,ab,clm. and circuit near2 simulat\$3	US-PGPUB;	
			Simulacys	EPO; JPO;	
	F:			DERWENT; IBM TDB	
	_ <sup>(A)</sup>	0	6243653.ph. and physical\$2 near3 test\$3	USPAT;	2004/05/21 10:40
	÷ .			US-PGPUB;	2004/05/21 10:40
	· · · · · · · · · · · · · · · · · · ·			EPO; JPO;	1
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				US-PGPUB;	1
-	1 14.8 3			EPO; JPO; DERWENT;	
				IBM TDB	
		0	(("6243653").PN.) and physical\$2 and	USPĀT;	2004/05/21 10:41
1			test\$3	US-PGPUB;	
	41			EPO; JPO;	
-	•			DERWENT;	
1		1	(("6243653").PN.) and test\$3	IBM TDB	2004/05/65 55
			it deligos film.) and testes	USPAT; US-PGPUB;	2004/05/21 10:41
				EPO; JPO;	,
	100			DERWENT;	
				IBM TDB	
		2	("6243653").PN.	USPAT;	2004/05/21 10:42
-	1			US-PGPUB;	
-	**	,		EPO; JPO;	
1				DERWENT;	
	_ '	o	physical\$2 near2 test\$3 and extract\$3	IBM TOB	2004/05/22
			near3 parasitic adj capaciance and	USPAT; US-PGPUB;	2004/05/21 10:43
1			simulat\$3	EPO; JPO;	
				DERWENT;	
1				IBM TDB	,
	-	1	physical\$2 near2 test\$3 and extract\$3	USPĀT,	2004/05/21 10:53
		ľ	near3 parasitic adj capacitance and	US-PGPUB;	
ľ		,	simulat\$3	EPO; JPO;	1
				DERWENT;	
		. 2	("5706206").PN.	IBM_TDB	
			, 5.55200 , .IN.	USPAT;	2004/05/21 11:10
4				US-PGPUB; EPO; JPO;	
-				DERWENT;	
L				IBM TDB	

11 <u></u>		<u> </u>				
	<del>-</del>	6	capacitance near3 test\$3 and capacitance	USPAT;	2004/05/21 11:1	5
. [	•		near3 design\$3 and parasitic adi	US-PGPUB;	2004/03/21 11:1	ا ٦
1		•	capacitance near4 test\$3 near6 design\$3	EPO; JPO;	. [	
				DERWENT;	.	
4						ł
,	<del></del>	1 6	capacitance near3 (physical test\$3) and	IBM_TDB	2004/05/01 11 1	
-			capacitance near3 (simulat\$3 design\$3 )	USPAT;	2004/05/21 11:1:	3
- 1			capacitance nears (simurates designss)	US-PGPUB;		ŀ
		1	and parasitic adj capacitance near4 test\$3	EPO; JPO;		
- 1	-		near6 design\$3	DERWENT;		- 1
1.				IBM TDB		ļ
1	-	45		USPAT;	2004/05/21 11:13	į
İ			capacitance near3 (simulat\$3 design\$3 )	US-PGPUB;		
	*		and parasitic adj capacitance	EPO; JPO;		- 1
-				DERWENT:		-
	•			IBM TDB		ĺ
-	-	56	(extracting extraction) near4 (parasitic	USPAT;	2004/05/24 19:39	J
ŀ			adj capacitance)	1.	2004/05/24 19:39	1
1				US-PGPUB;		1
		1		EPO; JPO;		
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1.			Market Ma	IBM_TDB		
		5	(extracting extraction) near4 (parasitic	USPAT;	2004/05/24 19:48	
1		1 1: 1	adj capacitance) and subtract\$3	US-PGPUB;		
.				EPO; JPO;		
1	•			DERWENT;		
- ]				IBM TDB		
-		2	(extracting extraction) near4 (parasitic	USPAT;	2004/05/24 19:56	
1			adj capacitance) and subtract\$3 and sum	US-PGPUB;	2004/05/24 19:56	1
		1	and sum		·	
1				EPO; JPO;		1
				DERWENT;		İ
_		5	low-months and sufficient	IBM_TDB		1
		]	(extracting extraction) near4 (parasitic	USPAT;	2004/05/24 19:56	1.
	: .		adj capacitance) and subtract\$3	US-PGPUB;		1
				EPO; JPO;		ı
	•			DERWENT;		
1	2. 1			IBM TDB		
-		6	raphael and parasitic adj capacitance and	USPAT:	2004/05/25 14:34	ŀ
ľ		'	three adj dimensional	US-PGPUB;	2004/05/25 14:54	Ι.
	•			EPO; JPO;		1
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.				DERWENT;	,	1
-		126	cmos and gate adj contact and parasitic	IBM_TDB	1	1
1		1	adj capacitance	USPAT;	2004/05/25 14:35	
i			adj Capacitance	US-PGPUB;	i	1
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				DERWENT;		L
1		_		IBM TDB		1.
1 -		84	width near2 gate and parasitic adj	USPAT;	2004/05/26 10:42	
1			capacitance and (extracting extraction)	US-PGPUB;	01,00,20 10.42	
1			1	EPO; JPO;		
-	e (1. 1. 1. 1. 1. 1. 1. 1. 1. 1. 1. 1. 1. 1			DERWENT;		1
1	* .					
-		2	width near2 gate and parasitic adj	IBM_TDB	0004405455	
1			capacitance near3 (extracting extraction)	USPAT;	2004/05/26 12:57	
1		,	oupdoicance hears (extracting extraction)	US-PGPUB;	* *	1
1.				EPO; JPO;		
1				DERWENT;		
1_				IBM_TDB		
1 -		.0	raphael.ti,ab,clm. and boundary adj	USPAT;	2004/05/26 12:57	İ
]		ļ	conditions	US-PGPUB;		ĺ
1			. '	EPO; JPO;		
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	· **			IBM TDB	•	ŀ
-	.	. 3	raphael and boundary adj conditions and	USPAT;	2004/05/06 10 55	
,		.	parasitic adj capacitance.ti,ab,clm.	f	2004/05/26 12:57	l
İ	1			US-PGPUB;	•	ľ
	,	İ		EPO; JPO;		ı
l	,			DERWENT;		ı
_		2	overlan manua and	IBM_TDB		
_		2	overlap near3 gate and parasitic adj	USPAT;	2004/05/27 13:17	ì
			capacitance and raphael	US-PGPUB;		
	.			EPO; JPO;		
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integrated circuit near3 operation.clm.  US-PGPUB; EFO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EFO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EFO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EFO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EFO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EFO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EFO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EFO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EFO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EFO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EFO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EFO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EFO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EFO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EFO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EFO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; EPO;	/05/28 1	5.10
apparatus near3 simulating near3 integrated adj circuit near3 operation.clm.  0 apparatus near6 simulating near6 integrated adj circuit near6 operation.clm.  0 apparatus near6 simulating near6 integrated adj circuit near6 operation.clm.  0 apparatus near6 simulating near6 integrated adj circuit near6 operation.ti,ab,clm.  1 apparatus near6 simulatis2 near6 integrated adj circuit near6 operation.ti,ab,clm.  2004 US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	, 0,5,20 1.	3.10
apparatus near3 simulating near3 integrated adj circuit near3 operation.clm.  0 apparatus near6 simulating near6 integrated adj circuit near6 operation.clm.  0 apparatus near6 simulating near6 integrated adj circuit near6 operation.clm.  0 apparatus near6 simulating near6 integrated adj circuit near6 operation.ti,ab,clm.  1 apparatus near6 simulatis2 near6 integrated adj circuit near6 operation.ti,ab,clm.  1 apparatus near6 simulatis2 near6 integrated adj circuit near6 operation.ti,ab,clm.  2004 US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;		,
apparatus near3 simulating near3 integrated adj circuit near3 operation.clm.  0 apparatus near6 simulating near6 integrated adj circuit near6 operation.clm.  0 apparatus near6 simulating near6 integrated adj circuit near6 operation.clm.  0 apparatus near6 simulating near6 integrated adj circuit near6 operation.ti,ab,clm.  1 apparatus near6 simulatis2 near6 integrated adj circuit near6 operation.ti,ab,clm.  1 apparatus near6 simulatis2 near6 integrated adj circuit near6 operation.ti,ab,clm.  1 apparatus near6 simulatis2 near6 integrated adj circuit near6 operation.ti,ab,clm.  2004 US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USFAT; US-PGPUB; EPO; JPO; DERWENT;		
apparatus near3 simulating near3 integrated adj circuit near3 operation.clm.   0 apparatus near6 simulating near6 integrated adj circuit near6 operation.clm.  1 apparatus near6 simulating near6 integrated adj circuit near6 operation.ti, ab, clm.  1 apparatus near6 simulatis2 near6 integrated adj circuit near6 operation.ti, ab, clm.  1 apparatus near6 simulatis2 near6 integrated adj circuit near6 operation.ti, ab, clm.  2004 USPAT; USPGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; USPAT; USPGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; USPGPUB; EPO; JPO; DERWENT;		
integrated adj circuit near3 operation.clm.  O apparatus near6 simulating near6 integrated adj circuit near6 operation.clm.  O apparatus near6 simulating near6 integrated adj circuit near6 operation.clm.  O apparatus near6 simulating near6 integrated adj circuit near6 operation.ti,ab,clm.  O apparatus near6 simulatis2 near6 integrated adj circuit near6 operation.ti,ab,clm.  I apparatus near6 simulati\$2 near6 integrated adj circuit near6 operation.ti,ab,clm.  O apparatus near6 simulati\$2 near6 integrated adj circuit near6 operation.ti,ab,clm.  O apparatus near6 simulati\$2 near6 integrated adj circuit near6 operation.ti,ab,clm.  O apparatus near6 simulati\$2 near6 integrated adj circuit near6 operation.ti,ab,clm.  O apparatus near6 simulati\$2 near6 integrated adj circuit near6 operation.ti,ab,clm.  O apparatus near6 simulati\$2 near6 integrated adj circuit near6 integrated adj circuit near6 operation.ti,ab,clm.  O apparatus near6 simulati\$2 near6 integrated adj circuit near6 integrated adj c	/05/28 1	5.18
operation.clm.    EPO; JPO; DERWENT; IBM_TDB   USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB   USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB   USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB   USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB   USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB   USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB   USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB   USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB   USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB   USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB   USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB   USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB   USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB   USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB   USPAT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT;	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	0.10
DERWENT; IBM_TDB USPĀT; US-PGPUB; ePO; JPO; DERWENT; IBM_TDB USPĀT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPĀT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPĀT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPĀT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPĀT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPĀT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPĀT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPĀT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPĀT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPĀT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPĀT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPĀT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPĀT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPĀT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPĀT; US-PGPUB; EPO; JPO; DERWENT;		
apparatus near6 simulating near6 integrated adj circuit near6 operation.clm.  0 apparatus near6 simulating near6 integrated adj circuit near6 operation.ti, ab, clm.  1 apparatus near6 simulatis2 near6 integrated adj circuit near6 operation.ti, ab, clm.  1 apparatus near6 simulatis2 near6 integrated adj circuit near6 operation.ti, ab, clm.  2004, US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;		1
apparatus near6 simulating near6 integrated adj circuit near6 operation.clm.  0 apparatus near6 simulating near6 integrated adj circuit near6 operation.ti, ab, clm.  1 apparatus near6 simulatis2 near6 integrated adj circuit near6 operation.ti, ab, clm.  1 apparatus near6 simulatis2 near6 integrated adj circuit near6 operation.ti, ab, clm.  2004, US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;		· 1
integrated adj circuit near6 operation.clm.    US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; Operation.ti,ab,clm.   apparatus near6 simulati\$2 near6 integrated adj circuit near6 operation.ti,ab,clm.   apparatus near6 simulati\$2 near6 integrated adj circuit near6 operation.ti,ab,clm.   4964   apparatus near6 simulati\$2.ti,ab,clm.   EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT;	/05/28 15	5:22
operation.clm.    EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; IBM_TDB USPAT; IBM_TDB USPAT; IBM_TDB USPAT; IBM_TDB USPAT; IBM_TDB USPAT; IBM_TDB USPAT; IBM_TDB USPAT; IBM_TDB USPAT; IBM_TDB USPAT; IBM_TDB USPAT; IBM_TDB USPAT; IBM_TDB USPAT; IBM_TDB USPAT; IBM_TDB USPAT; IBM_TDB USPAT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	. =	,
DERWENT; IBM TDB USPAT; US-PGPUB; epo; JPO; DERWENT; ilbm TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; ilbm TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; ilbm TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT;		
apparatus near6 simulating near6 integrated adj circuit near6 operation.ti,ab,clm.  1 apparatus near6 simulati\$2 near6 integrated adj circuit near6 operation.ti,ab,clm.  2004, US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; ePO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; ePO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; EPO; JPO; DERWENT; EPO; JPO; DERWENT;		ŀ
apparatus near6 simulating near6 integrated adj circuit near6 operation.ti,ab,clm.  1 apparatus near6 simulati\$2 near6 integrated adj circuit near6 operation.ti,ab,clm.  1 apparatus near6 simulati\$2 near6 integrated adj circuit near6 operation.ti,ab,clm.  4964 apparatus near6 simulati\$2.ti,ab,clm.  4964 apparatus near6 simulati\$2.ti,ab,clm.  4965 apparatus near6 simulati\$2.ti,ab,clm.  4087 apparatus near3 simulati\$2.ti,ab,clm.  4087 apparatus near3 simulati\$2.ti,ab,clm.  4087 apparatus near3 simulati\$2.ti,ab,clm.		1.
integrated adj circuit near6 operation.ti,ab,clm.  1 apparatus near6 simulati\$2 near6 integrated adj circuit near6 operation.ti,ab,clm.  1 apparatus near6 simulati\$2 near6 integrated adj circuit near6 operation.ti,ab,clm.  2004, US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT;	/05/28 15	5:23
operation.ti,ab,clm.  1 apparatus near6 simulati\$2 near6 integrated adj circuit near6 operation.ti,ab,clm.  4964 apparatus near6 simulati\$2.ti,ab,clm.  4965 apparatus near6 simulati\$2.ti,ab,clm.  4087 apparatus near3 simulati\$2.ti,ab,clm.  EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT;		
apparatus near6 simulati\$2 near6 integrated adj circuit near6 operation.ti,ab,clm.  4964 apparatus near6 simulati\$2.ti,ab,clm.  4967 apparatus near3 simulati\$2.ti,ab,clm.  IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT;		J
apparatus near6 simulati\$2 near6 integrated adj circuit near6 operation.ti,ab,clm.  4964 apparatus near6 simulati\$2.ti,ab,clm.  4967 apparatus near3 simulati\$2.ti,ab,clm.  IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT;	,	· †
integrated adj circuit near6 operation.ti,ab,clm.  4964 apparatus near6 simulati\$2.ti,ab,clm.  4087 apparatus near3 simulati\$2.ti,ab,clm.  US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT;		-
1ntegrated adj circuit near6 operation.ti,ab,clm.  4964 apparatus near6 simulati\$2.ti,ab,clm.  4965 apparatus near3 simulati\$2.ti,ab,clm.  4087 apparatus near3 simulati\$2.ti,ab,clm.  US-PGPUB; EPO; JPO; DERWENT; IBM TDB US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT;	05/28 15	5:24
DERWENT; IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; US-PGPUB; EPO; JPO; DERWENT; US-PGPUB; EPO; JPO; DERWENT;		1
4964 apparatus near6 simulati\$2.ti,ab,clm.  4087 apparatus near3 simulati\$2.ti,ab,clm.  IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; USPAT; US-PGPUB; EPO; JPO; DERWENT;		ŀ
4964 apparatus near6 simulati\$2.ti,ab,clm.  4087 apparatus near3 simulati\$2.ti,ab,clm.  USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;		
4087 apparatus near3 simulati\$2.ti,ab,clm.  4087 daparatus near3 simulati\$2.ti,ab,clm.  4087 daparatus near3 simulati\$2.ti,ab,clm.  4087 daparatus near3 simulati\$2.ti,ab,clm.  4087 daparatus near3 simulati\$2.ti,ab,clm.		4.
4087 apparatus near3 simulati\$2.ti,ab,clm.  US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	05/28 15	5:24
4087 apparatus near3 simulati\$2.ti,ab,clm.  DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;		1
apparatus near3 simulati\$2.ti,ab,clm.  IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;		,
4087 apparatus near3 simulati\$2.ti,ab,clm. USPAT; 2004/US-PGPUB; EPO; JPO; DERWENT;	•	ļ
US-PGPUB; EPO; JPO; DERWENT;		ſ
US-PGPUB; EPO; JPO; DERWENT;	05/28 15	5:25
DERWENT;		-1
IBM TDB		

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-	383	apparatus near3 simulati\$2 near6	USPAT;	2004/05/28 15:26
		(semiconductor integrated	US-PGPUB;	]
1 .	-	circuit).ti,ab,clm.	EPO; JPO;	· .
, ·			DERWENT;	
			IBM TDB	
	4	039484.ap.	USPAT;	2004/05/28 19:16
			US-PGPUB;	
	100		EPO; JPO;	1 .1
			DERWENT;	
	re-		IBM TDB	
ļ <del>+</del>	2	("6169302").PN.	USPAT;	2004/05/29 18:06
	,		US-PGPUB;	
	٠,		EPO; JPO;	
1	200		DERWENT;	
			IBM TDB	
-	62	apparatus near3 simulating near3	USPAT;	2004/05/29 18:06
, ,		circuit.ti,ab,clm.	US-PGPUB;	
			EPO; JPO;	
,	,		DERWENT;	
			IBM TDB	
-	7	apparatus near3 simulating near3	USPAT;	2004/05/29 18:07
,	200	circuit.ti,ab,clm. and computer.ti,ab,clm.	US-PGPUB;	
		and processor ti, ab, clm. and	EPO; JPO;	
	. ,	memory.ti,ab,clm.	DERWENT;	
2.12.1			IBM TDB	